

<b>Notice of References Cited</b>	Application/Control No. 10/040,797	Applicant(s)/Patent Under Reexamination GOLDFINE ET AL.	
	Examiner Jeffrey R. West	Art Unit 2857	Page 1 of 1

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*	B	US-5,394,084	02-1995	Snyder	324/225
*	C	US-5,223,796	06-1993	Waldman et al.	324/687
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	M	US-			

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**NON-PATENT DOCUMENTS**

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*	U	Zaretsky et al., "Continuum Properties from Interdigital Electrode Dielectrometry", IEEE Transactions on Electrical Insulation, Vol. 23, No. 6. December 1988.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.